

FIELD EMISSION SCANNING ELECTRON MICROSCOPY



Make: Carl Zeiss, Germany

Model: SUPRA 55VP, Gemini Column.
With air lock system

Detectors:

- 1, Secondary Electron 1 (In Lens)
- 2, Secondary Electron 2(SE2)
- 3, Backscattered Electron (BSE)
- 4, VPSE (Variable Pressure Mode)

Energy Dispersive X-ray Analysis (Edx)

Oxford Instruments X-MAX (20mm²)

Resolution: 1.2 nm gold particle separation on a carbon substrate

Magnification: From a min of 100x to greater than 5, 00,000 X

Description

SUPRA 55VP FE-SEM is a general purpose ultra high resolution FE-SEM based on the unique GEMINI Technology. It provided excellent imaging properties combined with analytical capabilities which make this high end FE-SEM suitable for a wide range of applications in materials science, life science and semiconductor technology. The large specimen chamber for the integration of optional detectors and accessories enables the user to configure the SUPRA for specific applications without sacrificing productivity or efficiency.

Sample requirement

sample should be in dried condition and it can be powder, film, pellet , coating ect..